

ABSTRACT

Reducing the process, increasing the number of transistors and metal connections in highly integrated circuits in accordance with Moore's law leads to an increase in the number of parameters that need to be monitored. This, in turn, leads to the generation of a large amount of measured data, processing and analysis of which are the key to optimization and control of the technological process.

The control of the output of the fittings is an extremely important part of the microelectronic technology, since it depends on both direct economic benefits from product production and other important economic indicators, such as time to market and time of management.

The subject of the study of this work is the development of a special software for the automatic monitoring of the status of the process in real time. The paper describes the possibilities of typical industrial equipment for the testing of microcircuits and their use.

VLSI TESTING, AUTOMATIC TEST EQUIPMENT, TIME DEPENDENT DEFECT, BIG DATA.